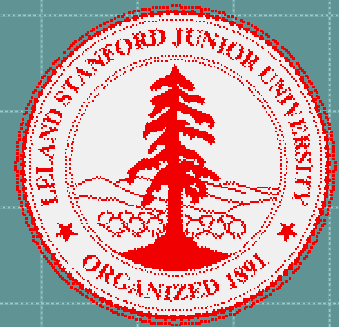


# Solving Device PDE's with the PROPHET Simulator

<http://www-tcad.stanford.edu/~prophet/>

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With contributions from  
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Conor Rafferty (Agere Systems)

# Outline

- ◆ What is PROPHET?
- ◆ Specifying PDE's for PROPHET to solve
- ◆ Discretization on a mesh
- ◆ Applications
- ◆ Summary

# What is PROPHET?

- ◆ Developed at Bell Labs as a process simulator
- ◆ Released externally as a TCAD simulation *platform* (Stanford, UT Austin, and Conor Rafferty added device simulation capabilities)
- ◆ Permits user-level specification of PDE's created from reusable operators

# PROPHET Overview

**User interface:**

Input parser

Graphics/postprocessing

**Modules:**

Solve

Grid

Field

Bias

...

**Libraries:**

Database

Structure

Linear solver

**PDE Engine:**

Assembly

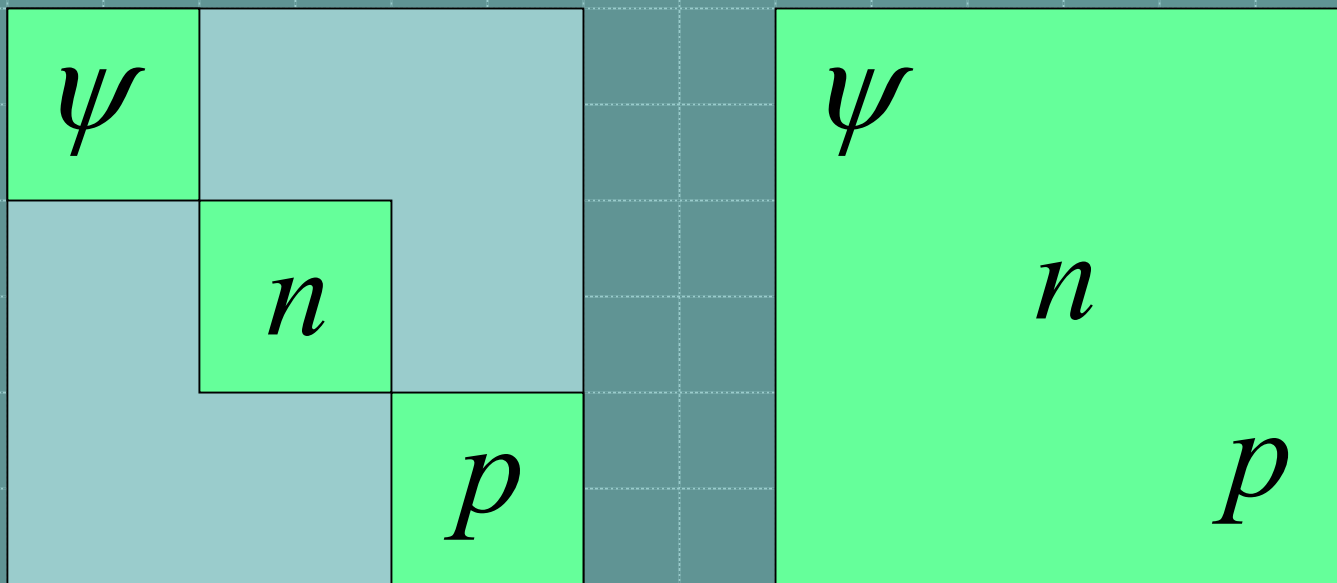
Solvers

Discretization  
(geometric)

Models  
(physical)

# Representing Physical Systems in PROPHET

Global system is composed of blocks of PDE's



Loosely Coupled

Tightly Coupled

# Representing PDE's in PROPHET

- ◆ PDE is a sum of terms (well, almost)
- ◆ Terms are a combination of geometric and physical operators:  $\text{PDE} = G_1 P_1 + G_2 P_2 + G_3 P_3$
- ◆ Geometric operator:  $\nabla \times, \nabla \cdot, \partial/\partial t$
- ◆ Physical operator:  $\text{flux} = f(A, \nabla A, X, \nabla X, \dots)$
- ◆ Functions permit evaluation of intermediate values with chaining back to solution variables

# Geometric Operators

- ◆ Spatial operators: divergence, nodal
- ◆ Differentiation wrt time
- ◆ Interface flux
- ◆ Dirichlet
- ◆ Constraint
- ◆ Interface algebraic

# Physical Operators

- ◆ Algebraic building blocks: +, -, \*, /, sqrt, exp, etc.
- ◆ Fluxes:  $-\varepsilon \nabla \psi$ ,  $n \mu \nabla \psi - D \nabla n$
- ◆ Many domain-specific expressions:
  - ◆ space charge density
  - ◆ mobility
  - ◆ device contact boundary conditions
  - ◆ Shockley-Reed-Hall and Auger recombination



# Specifying Terms

`<geo_op>.<phy_op>(<inputs>|<outputs>)@{<where>}`

$$\nabla \cdot (\epsilon \psi)$$

`box_div.lapflux(psi|psi)@{silicon,poly,oxide}`

$$q(p - n + N_D^+ - N_A^-)$$

`nodal.nscd(electrons,holes,netdope|psi)@{silicon,poly}`

`constraint.continuity(0|psi)@{silicon/oxide,poly/oxide}`

`dirichlet.device_dirichlet(netdope|psi)@{CONTACTS}`

# Specifying Systems (PDE block)

```
system name=silicon_poisson
+ sysvars=psi
+ term0=ndiv_fbm.lapflux(psi|psi)@{SEMICONDUCTORS,INSULATORS}
+ term1=nodal.nscd(electrons,holes,netdope|psi)@{SEMICONDUCTORS}
+ term2=dirichlet.device_dirichlet(netdope|psi)@{CONTACTS}
+ term3=constraint.continuity(psi|psi)@{ALL_INTERFACES}
+ tmpvars=electrons,holes
+ func0=quasiFermi(psi|electrons,holes)@{SEMICONDUCTORS}
```

# Solution Methods

- ◆ Timestepping
  - ◆ typically TR/BDF2 with LTE-based timestep control
- ◆ PDE block staggering
- ◆ Newton nonlinear algorithm on a single block
  - ◆ convergence detection in residual and/or update norm
  - ◆ range clamping
  - ◆ damping
- ◆ Small signal AC, preliminary harmonic balance

# Discretization

Apply Gauss' Theorem

$$\nabla \cdot \mathbf{F} = U = \frac{\partial u}{\partial t} + G - R$$

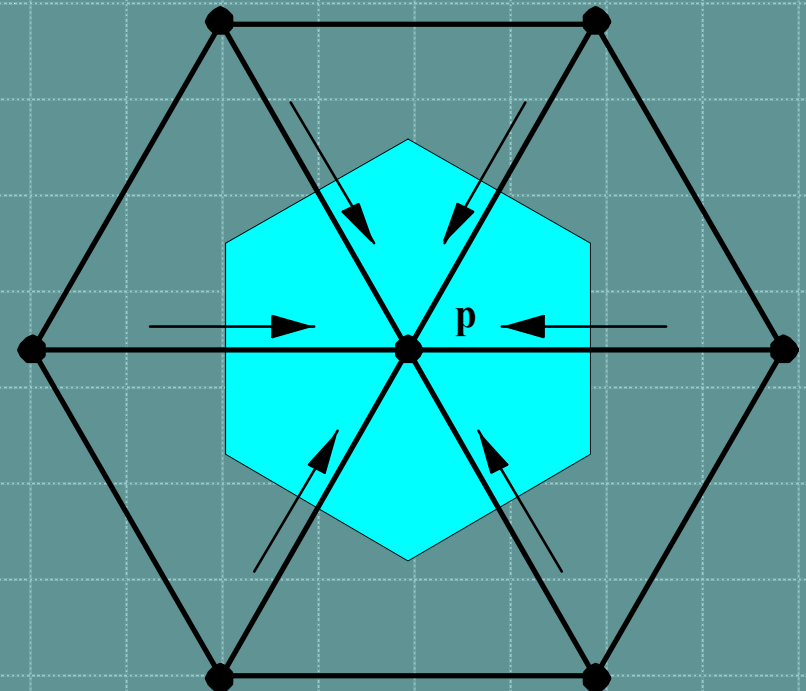
$$\oint_{\Omega_{CV}} \nabla \cdot \mathbf{F} d\Omega - \int_{\Omega_{CV}} U d\Omega = 0$$

$$\oint_{S_{CV}} \mathbf{F} \cdot \hat{\mathbf{n}} dS - \int_{\Omega_{CV}} U d\Omega = 0$$

Approximate on a mesh

$$\oint_{S_p} \mathbf{F} \cdot \hat{\mathbf{n}} dS = \sum_i F_{i,p} l_i$$

$$\int_{\Omega_p} U d\Omega = U_p V_p$$

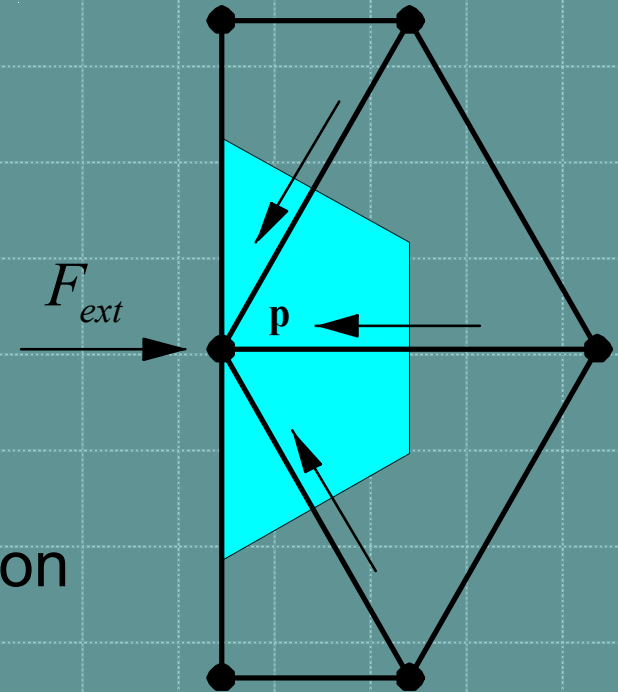


# Interfaces

Control volume integration is “closed” by including external flux

$$\oint_{S_p} \mathbf{F} \cdot \hat{n} dS = F_{ext} l_p + \sum_i F_{i,p} l_i$$

Thus, the natural boundary condition is zero-flux if equation has no interface flux terms

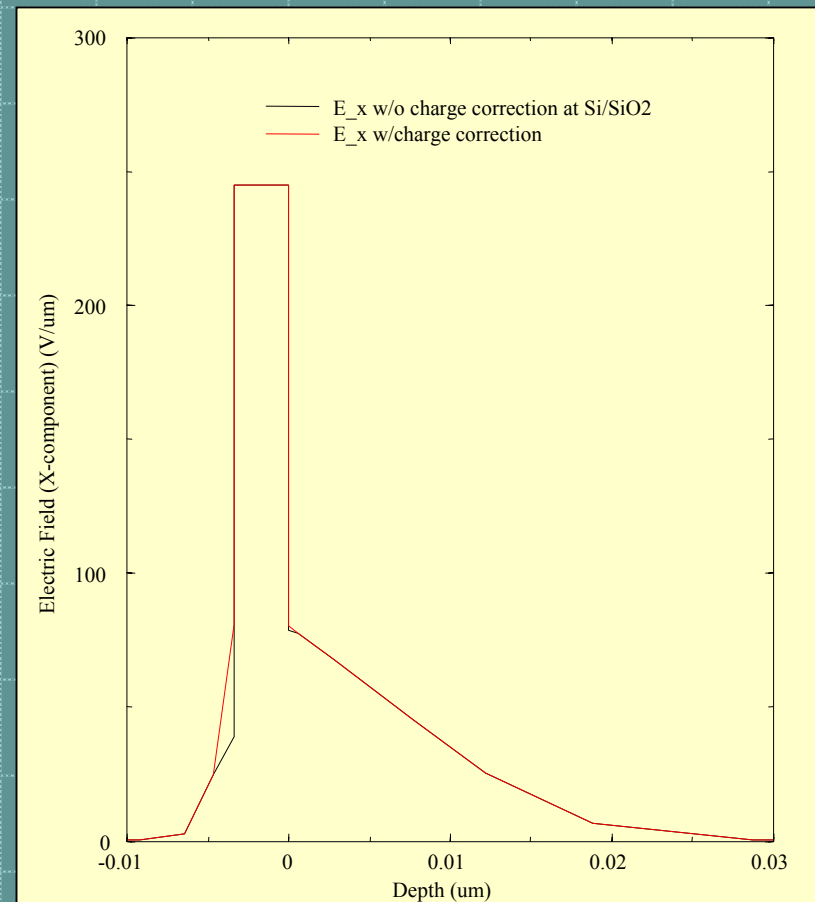
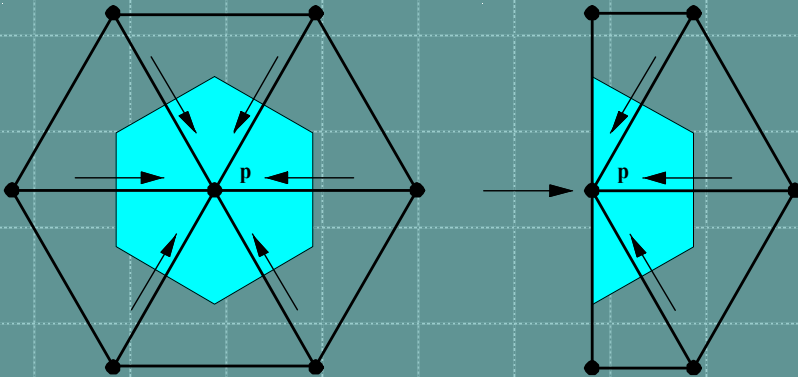


# Evaluating the “Real” Flux

$$\nabla \cdot \mathbf{j}_n = -q \nabla \cdot (n \mu \nabla \psi - D \nabla n)$$

$$\mu = \mu(N, T_L, E_{\square}, E_{\perp})$$

$$E_{\square} = \frac{|\mathbf{E} \cdot \mathbf{j}|}{|\mathbf{j}|}, \quad E_{\perp} = \frac{|\mathbf{E} \times \mathbf{j}|}{|\mathbf{j}|}$$



# Applications

- ◆ Modeling quantum effects via Density Gradient
- ◆ Laser simulation
- ◆ Interconnect interactions with substrate (device level frequency domain)

# Density Gradient

Models quantum confinement of particles adjacent to silicon/oxide interface. The large chemical potential barrier of the insulator requires the wave function to vanish at the interface. Continuity of this wave function pushes carriers away from the barrier.

$$\mathbf{F}_n = -D_n \nabla n + \mu_n n \nabla \psi + 2\mu_n n \frac{\hbar^2}{4lq m_n^*} \nabla \left( \frac{\nabla^2 \sqrt{n}}{\sqrt{n}} \right)$$

Quantum potential:  $2b_n \frac{\nabla^2 \sqrt{n}}{\sqrt{n}}$



# Density Gradient System

$$\nabla \cdot (\epsilon \psi) + q(p - n + N_D^+ - N_A^-) = 0$$

$$\nabla \cdot (b_n \nabla \sqrt{n}) + \frac{\sqrt{n}}{2} \left( \psi - \frac{kT}{q} \ln \frac{n}{n_i} - \phi_n \right) = 0$$

$$\nabla \cdot (b_p \nabla \sqrt{p}) + \frac{\sqrt{p}}{2} \left( \psi + \frac{kT}{q} \ln \frac{p}{p_i} - \phi_p \right) = 0$$

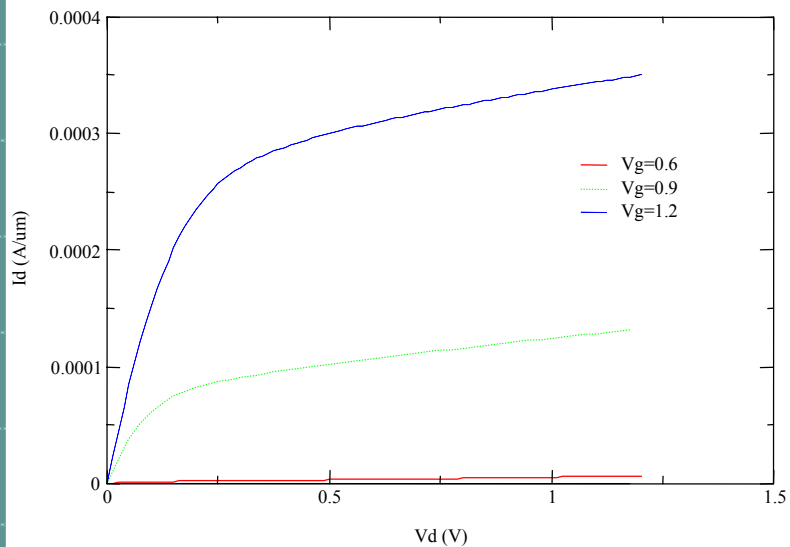
$$\frac{\partial n}{\partial t} + \nabla \cdot (\mu_n n \nabla \phi_n) + r = 0$$

$$\frac{\partial p}{\partial t} - \nabla \cdot (\mu_p p \nabla \phi_p) + r = 0$$

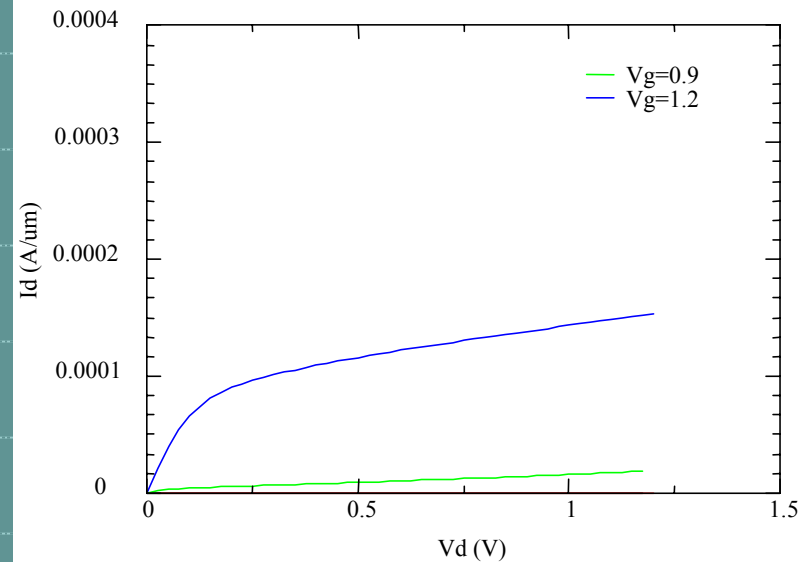
# Classical DD vs. Density Gradient

MIT 50nm well-tempered MOSFET

Classical drift-diffusion



Density Gradient



# Photon Generation in a Laser

$$\nabla \cdot (\epsilon \nabla \psi) + q(p - n + N_D^+ - N_A^-) = 0$$

$$-\nabla \cdot (-\mathbf{F}_n) + r_{SRH} + r_{Auger} + B_{\text{field}} np + r_{st} = 0$$

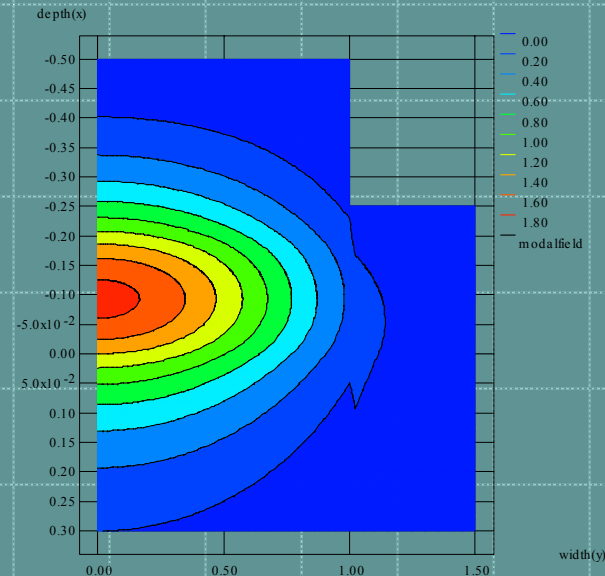
$$-\nabla \cdot (-\mathbf{F}_p) + r_{SRH} + r_{Auger} + B_{\text{field}} np + r_{st} = 0$$

$$-\nabla \cdot (\kappa \nabla T_L) - \nabla \cdot (-\psi \mathbf{j}) = 0$$

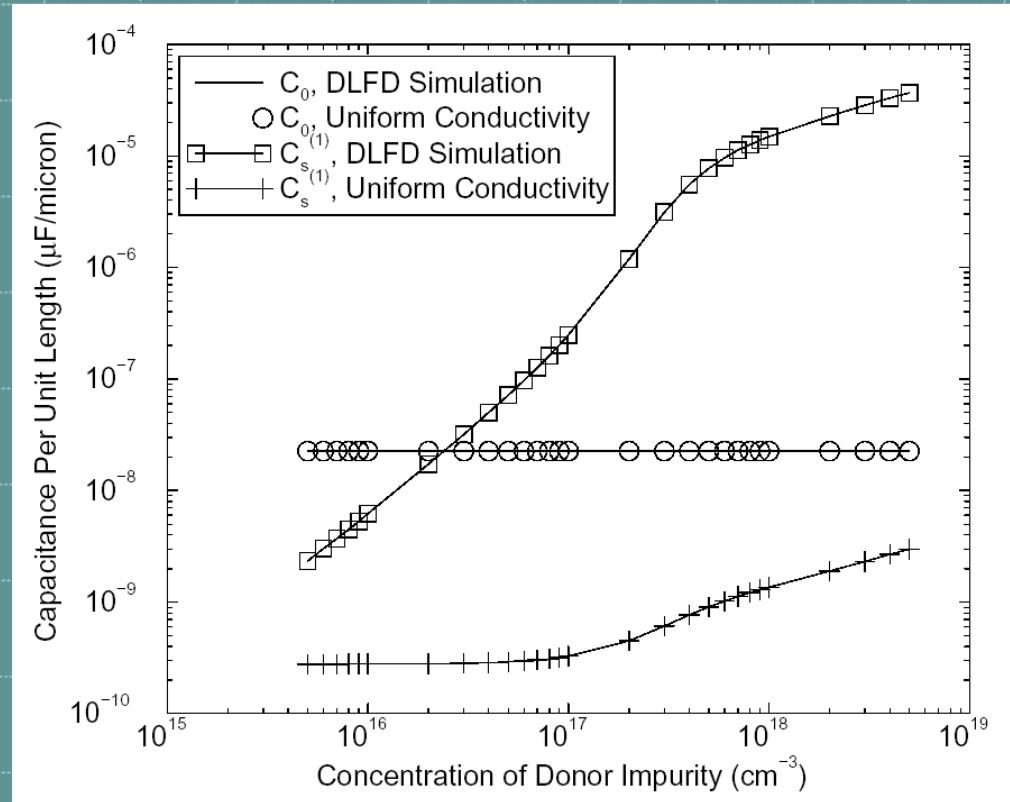
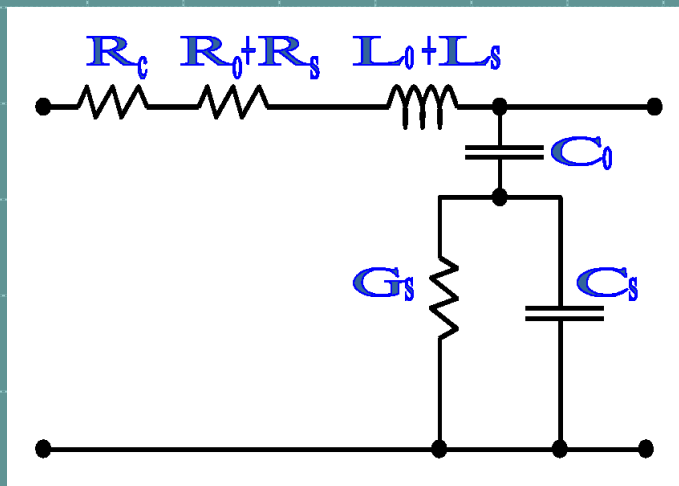
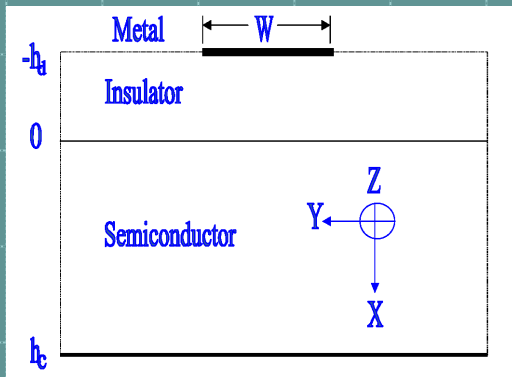
$$(v_g G - 1/\tau) N_p + \beta_{sp} R_{sp} = 0$$

1.55 micron InGaAs/InP  
Edge Emitting Laser  
Intensity of dominant mode

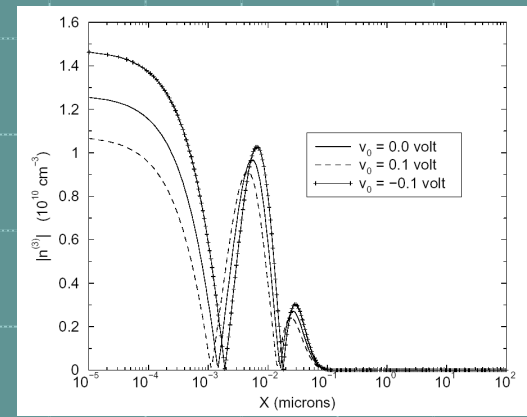
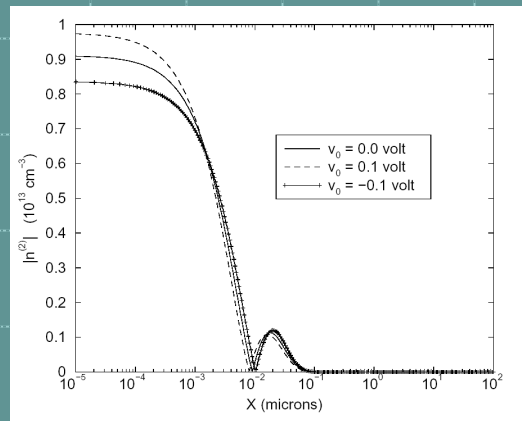
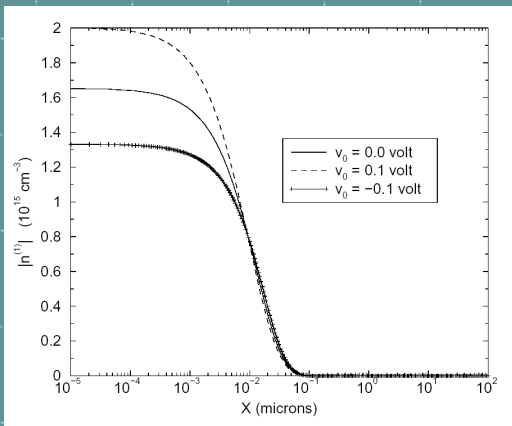
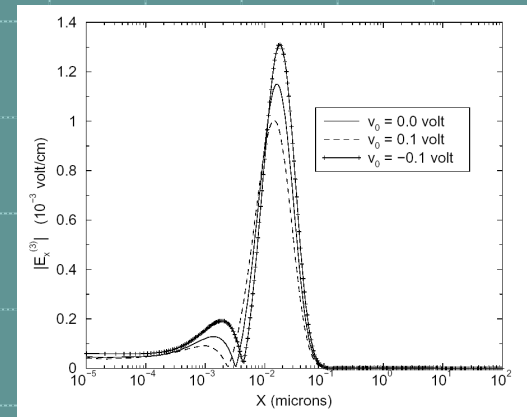
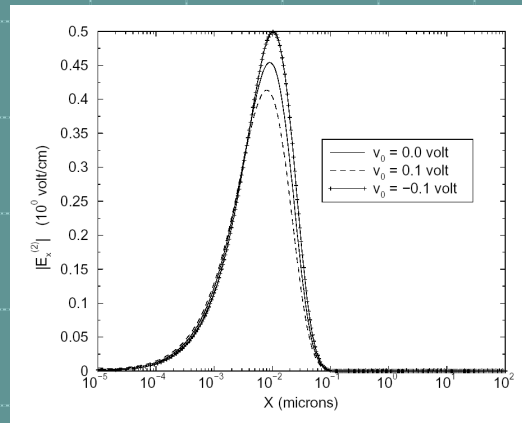
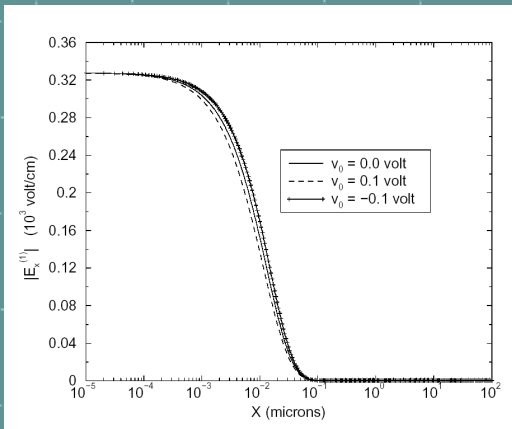
Last equation is lumped (scalar),  
but dependent on distributed  
spontaneous emission rate



# Interconnect/substrate



# Bias Effects on the Substrate



# Summary -- Advantages

- ◆ Rapid prototyping
- ◆ Simulation on real structures
- ◆ Reasonable efficiency (extra assembly overhead is fairly minimal)
- ◆ Partial box method
- ◆ Code reuse means fewer errors
- ◆ Model debugging aids

# Drawbacks and Needs

- ◆ Diagnostics
- ◆ Still looking for faster and more robust linear solvers. We use Berkeley Sparse and PETSc (sparse direct, ILU+GMRES, ILU+BiCGstab)
- ◆ Recovery from failed Newton is through load control (reduce time step or bias change). What alternatives have been tried and how well do they work?